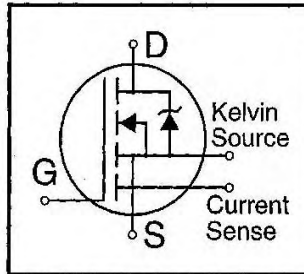


# IRC830PbF

## HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Current Sense
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Lead-Free



$$V_{DS} = 500V$$

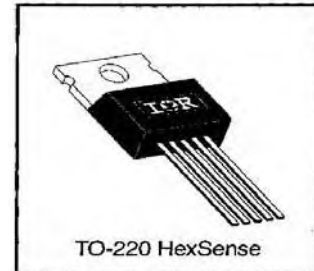
$$R_{DS(on)} = 1.5\Omega$$

$$I_D = 4.5A$$

### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The HEXSense device provides an accurate fraction of the drain current through the additional two leads to be used for control or protection of the device. These devices exhibit similar electrical and thermal characteristics as their IRF-series equivalent part numbers. The provision of a kelvin source connection effectively eliminates problems of common source inductance when the HEXSense is used as a fast, high-current switch in non current-sensing applications.



### Absolute Maximum Ratings

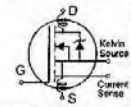
	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	4.5	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	3.0	
$I_{DM}$	Pulsed Drain Current ①	18	
$P_D @ T_C = 25^\circ C$	Power Dissipation	74	W
	Linear Derating Factor	0.59	W/°C
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy ②	280	mJ
$I_{AR}$	Avalanche Current ①	4.5	A
$E_{AR}$	Repetitive Avalanche Energy ①	7.4	mJ
dv/dt	Peak Diode Recovery dv/dt ③	3.5	V/ns
$T_J$	Operating Junction and	-55 to +150	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds		
	Mounting Torque, 6-32 or M3 screw	10 lbf·in (1.1 N·m)	

### Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	—	1.7	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	—	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient	—	—	62	

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	500	—	—	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	0.61	—	V/°C	Reference to 25°C, I <sub>D</sub> =1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	1.5	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =2.7A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	—	4.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
g <sub>fs</sub>	Forward Transconductance	2.7	—	—	S	V <sub>DS</sub> =50V, I <sub>D</sub> =2.7A ④
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	25	μA	V <sub>DS</sub> =500V, V <sub>GS</sub> =0V
		—	—	250	μA	V <sub>DS</sub> =400V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> =20V
	Gate-to-Source Reverse Leakage	—	—	-100	nA	V <sub>GS</sub> =-20V
Q <sub>g</sub>	Total Gate Charge	—	—	38	nC	I <sub>D</sub> =3.1A
Q <sub>gs</sub>	Gate-to-Source Charge	—	—	5.0	nC	V <sub>DS</sub> =400V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	—	—	22	nC	V <sub>GS</sub> =10V See Fig. 6 and 13 ④
t <sub>d(on)</sub>	Turn-On Delay Time	—	8.2	—	ns	V <sub>DD</sub> =250V
t <sub>r</sub>	Rise Time	—	16	—	ns	I <sub>D</sub> =3.1A
t <sub>d(off)</sub>	Turn-Off Delay Time	—	42	—	ns	R <sub>G</sub> =12Ω
t <sub>f</sub>	Fall Time	—	16	—	ns	R <sub>D</sub> =79Ω See Figure 10 ④
L <sub>D</sub>	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6 mm (0.25in.) from package and center of die contact
L <sub>S</sub>	Internal Source Inductance	—	7.5	—	nH	
C <sub>iss</sub>	Input Capacitance	—	610	—	pF	V <sub>GS</sub> =0V
C <sub>oss</sub>	Output Capacitance	—	91	—	pF	V <sub>DS</sub> =25V
C <sub>rss</sub>	Reverse Transfer Capacitance	—	68	—	pF	f=1.0MHz See Figure 5
r	Current Sensing Ratio	1440	—	1600	—	I <sub>D</sub> =4.5A, V <sub>GS</sub> =10V
C <sub>oss</sub>	Output Capacitance of Sensing Cells	—	9.0	—	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, f=1.0MHz

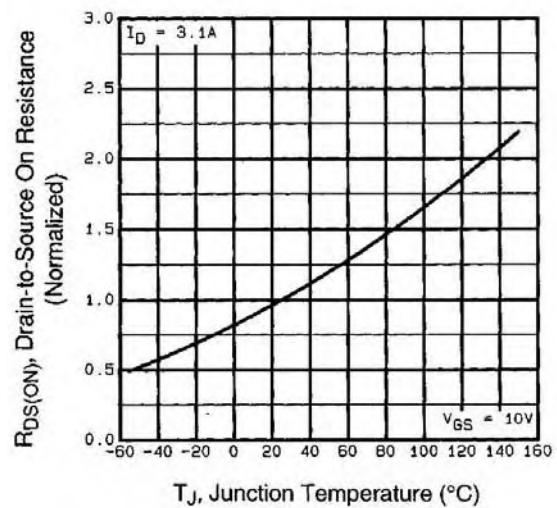
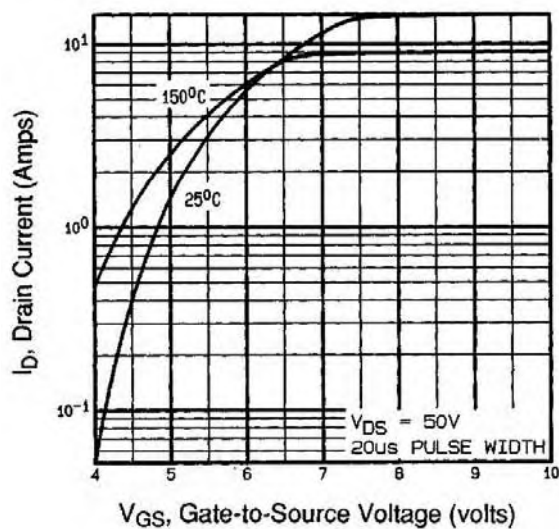
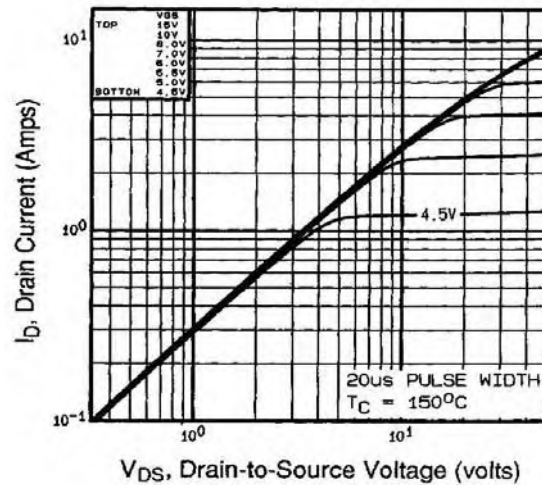
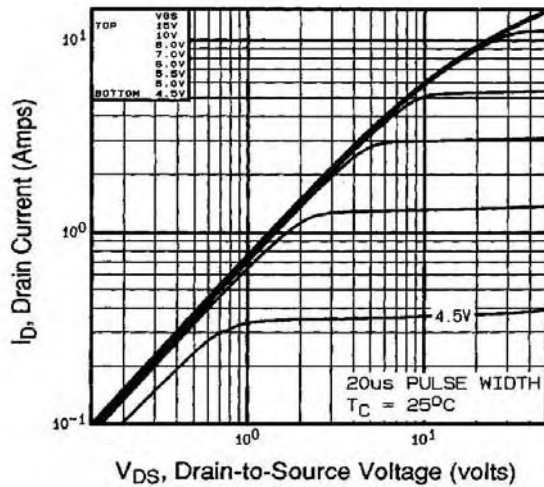


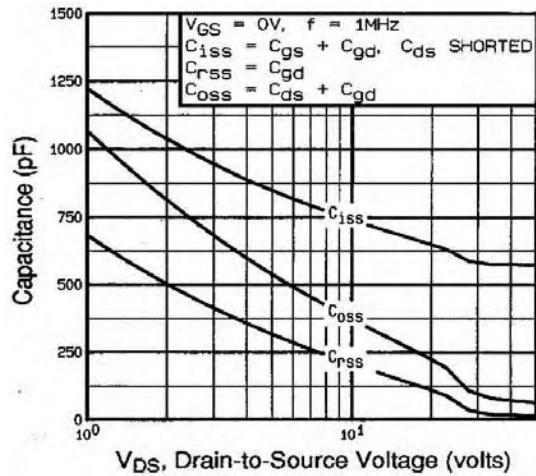
## Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	4.5	A	MOSFET symbol showing the integral reverse p-n junction diode.
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	18	A	
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.6	V	T <sub>J</sub> =25°C, I <sub>S</sub> =4.5A, V <sub>GS</sub> =0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	320	640	ns	T <sub>J</sub> =25°C, I <sub>F</sub> =3.1A
Q <sub>rr</sub>	Reverse Recovery Charge	—	1.0	2.0	μC	di/dt=100A/μs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

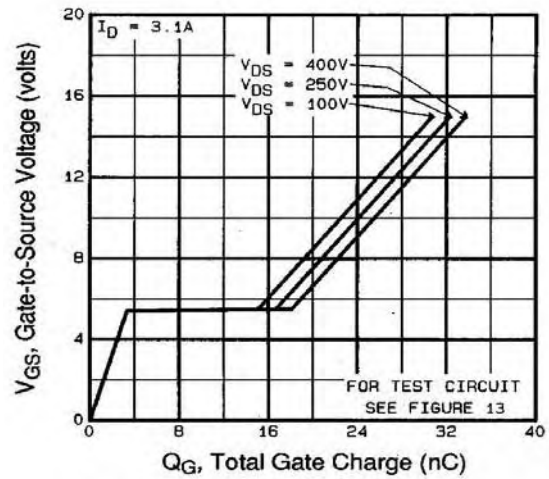
Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ② V<sub>DD</sub>=50V, starting T<sub>J</sub>=25°C, L=24mH, R<sub>G</sub>=25Ω, I<sub>AS</sub>=4.5A (See Figure 12)
- ③ I<sub>SD</sub>≤4.5A, di/dt≤75A/μs, V<sub>DD</sub>≤V<sub>(BR)DSS</sub>, T<sub>J</sub>≤150°C
- ④ Pulse width ≤ 300 μs; duty cycle ≤2%.

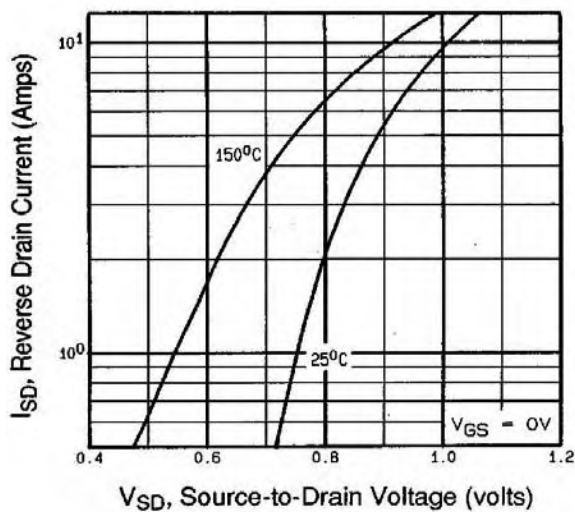




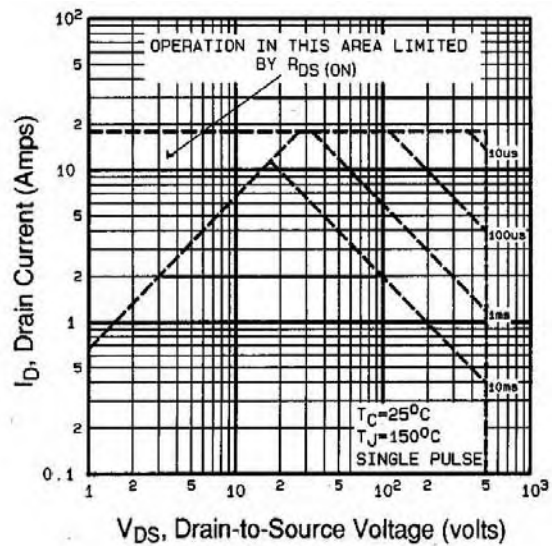
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



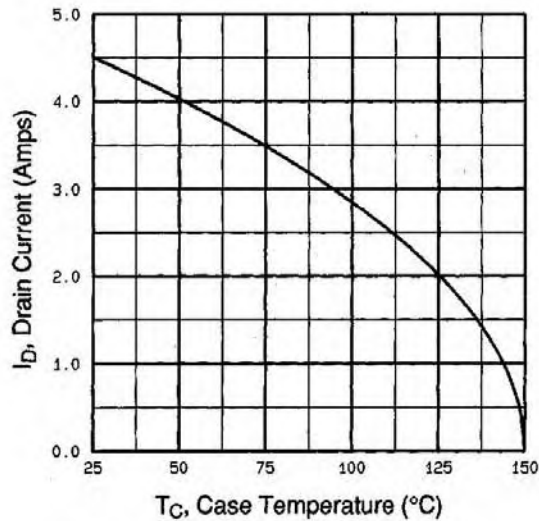
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



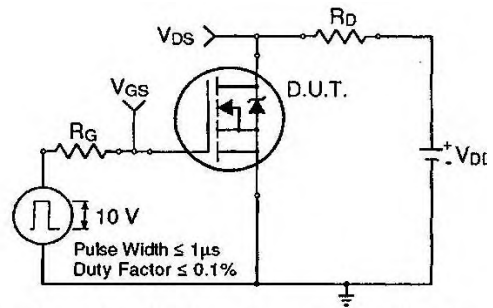
**Fig 7.** Typical Source-Drain Diode Forward Voltage



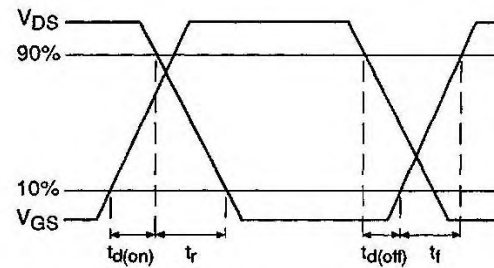
**Fig 8.** Maximum Safe Operating Area



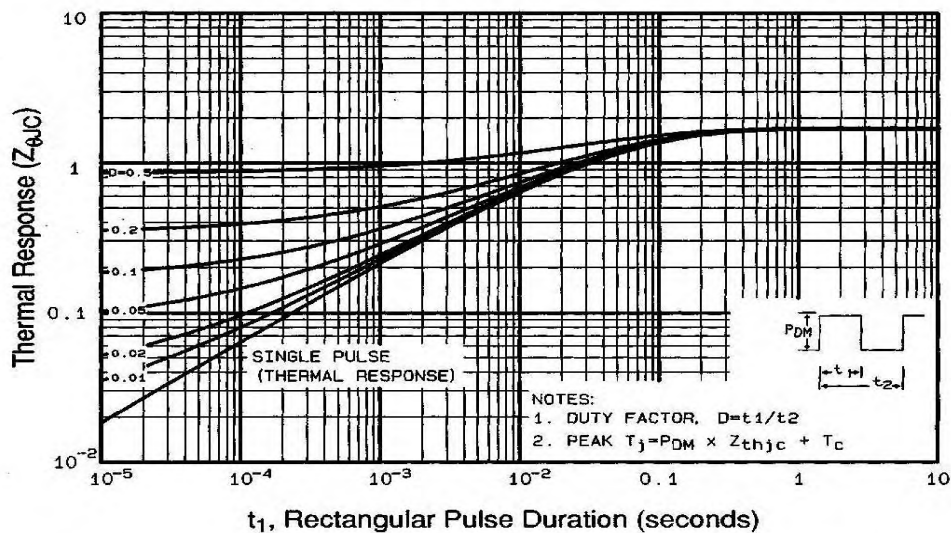
**Fig 9.** Maximum Drain Current Vs. Case Temperature



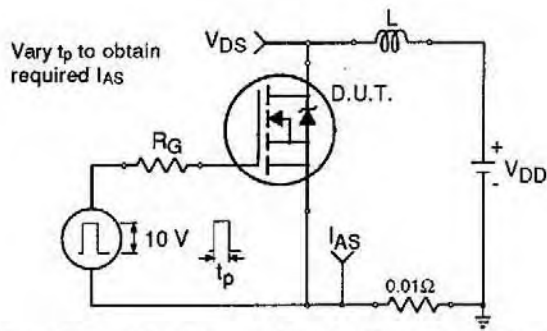
**Fig 10a.** Switching Time Test Circuit



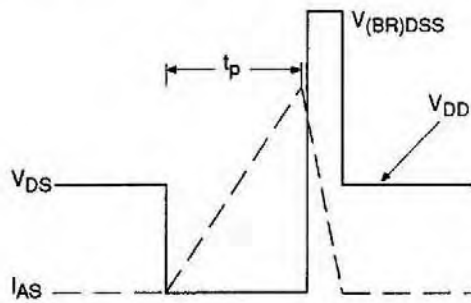
**Fig 10b.** Switching Time Waveforms



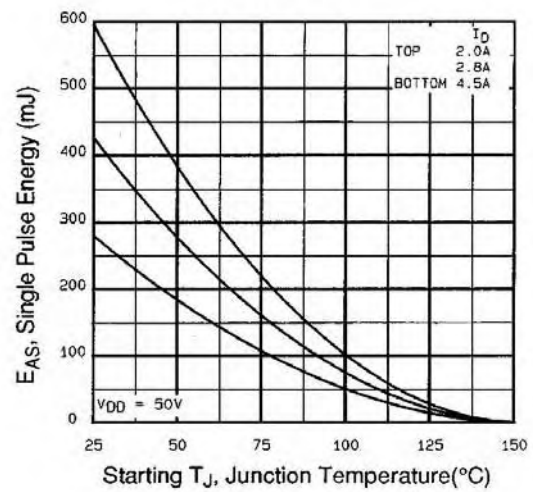
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



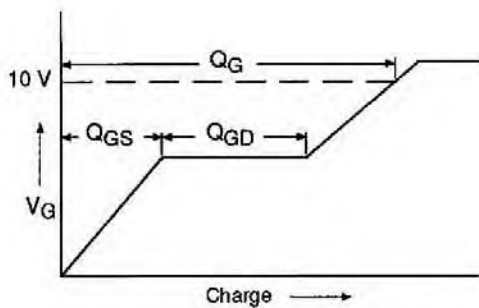
**Fig 12a.** Unclamped Inductive Test Circuit



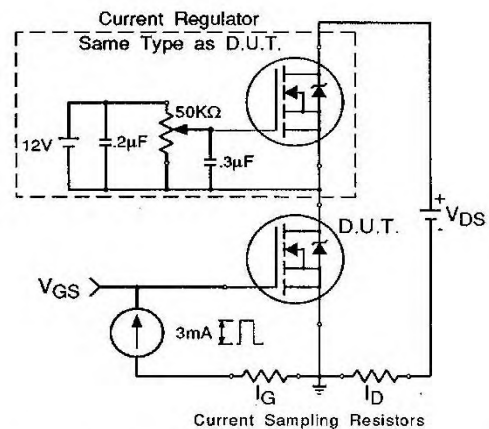
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



**Fig 13a.** Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit

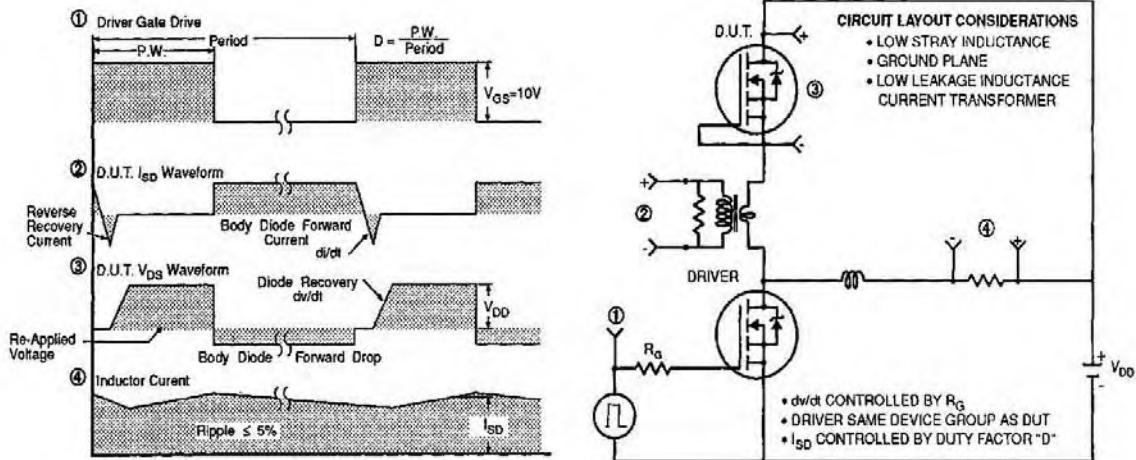


Fig 14. Peak Diode Recovery  $dv/dt$  Test Circuit

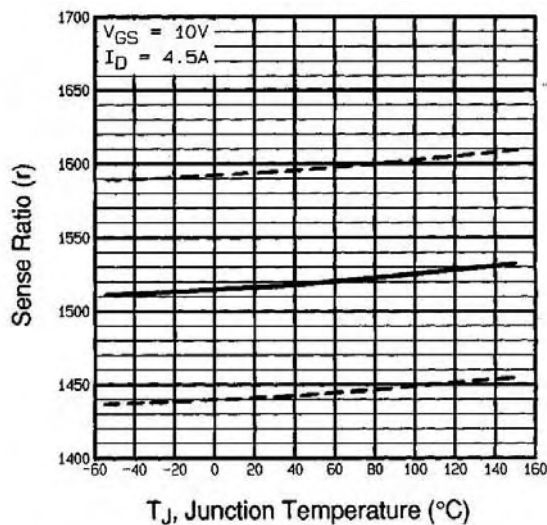


Fig 15. Typical HEXSense Ratio Vs. Junction Temperature

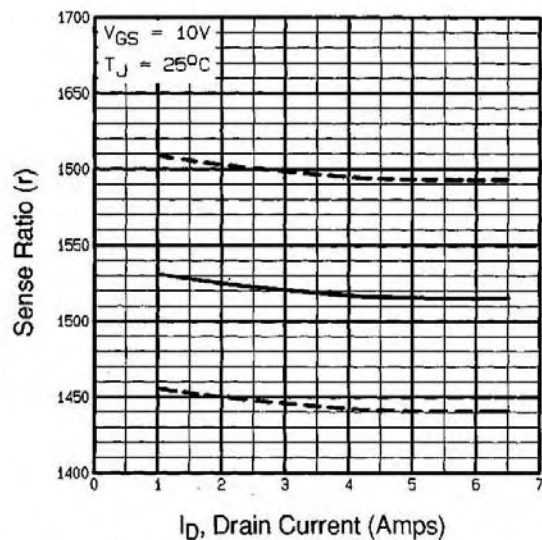
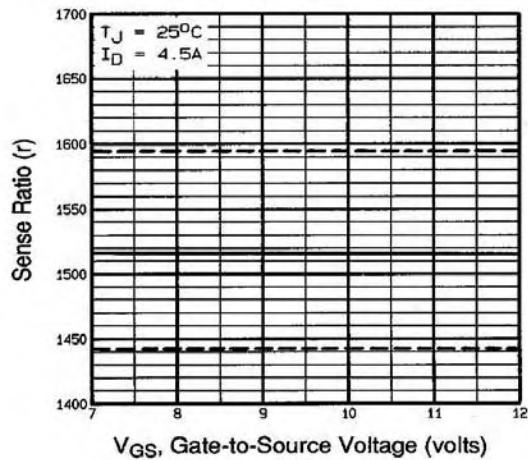
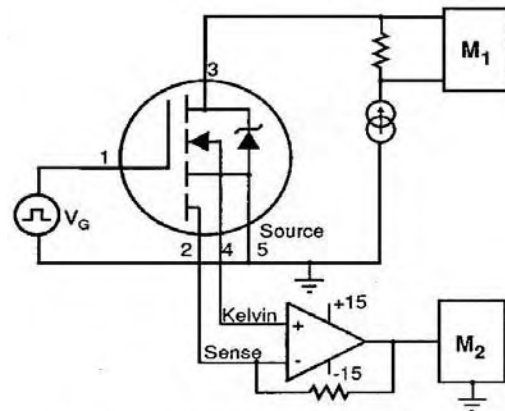


Fig 16. Typical HEXSense Ratio Vs. Drain Current

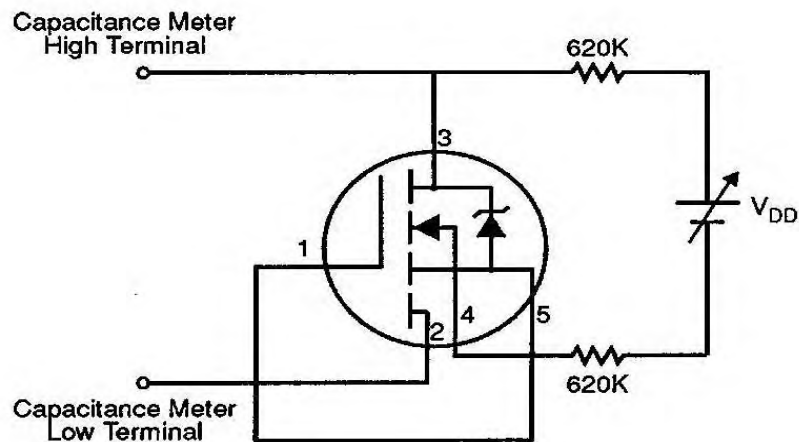


**Fig 17.** Typical HEXSense Ratio Vs. Gate Voltage



$M_1, M_2$  = HIGH SPEED DIGITAL VOLTMETERS

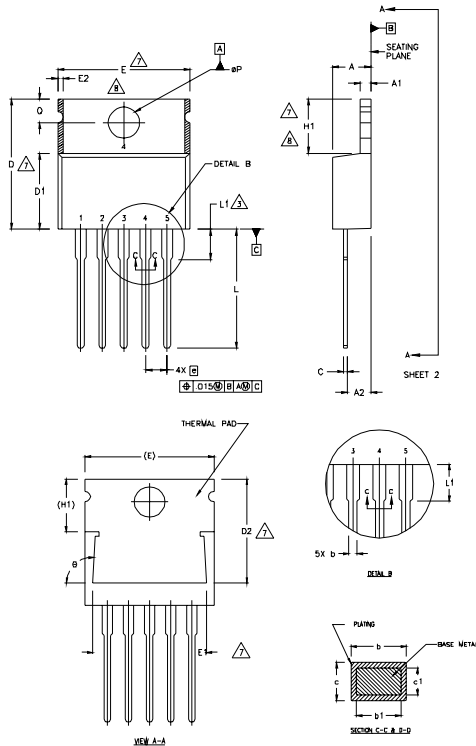
**Fig 18.** HEXSense Ratio Test Circuit



**Fig 19.** HEXSense Sensing Cell Output Capacitance Test Circuit

## HexsenseTO-220 5L Package Outline

( Dimensions are shown in millimeters (inches) )



### NOTES:

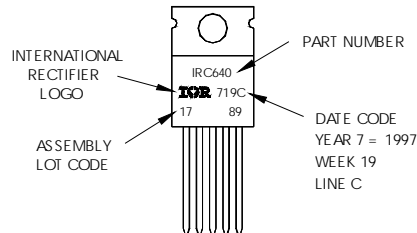
- 1 DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- 2 DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
- 3 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
- 4 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5 DIMENSION b1 & c1 APPLY TO BASE METAL ONLY.
- 6 CONTROLLING DIMENSION : INCHES.
- 7 THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- 8 DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.

SYMBOL	DIMENSIONS				NOTES
	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
A	3.56	4.82	.140	.190	5
A1	0.51	1.40	.020	.055	
A2	2.04	2.92	.080	.115	
b	0.64	0.88	.025	.035	
b1	0.64	0.84	.025	.033	
c	0.36	0.61	.014	.024	5
c1	0.36	0.56	.014	.022	
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	7
D2	12.19	12.88	.480	.507	
E	9.66	10.66	.380	.420	
E1	8.38	8.89	.330	.350	4,7
e	1.70 BSC		.067 BSC		7
H1	5.85	6.55	.230	.270	7,8
L	13.47	14.09	.530	.555	
L1	—	6.35	—	.250	3
ØP	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	
ø	90°—93°		90°—93°		

## Hexsense TO-220 5L Part Marking Information

EXAMPLE: THIS IS AN IRC640  
WITH ASSEMBLY  
LOT CODE 1789  
ASSEMBLED ON WW19, 1997  
IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position  
indicates "Lead-Free"



Data and specifications subject to change without notice.



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